



imec

Bias dependent admittance spectroscopy of thin film solar cells: Simulations

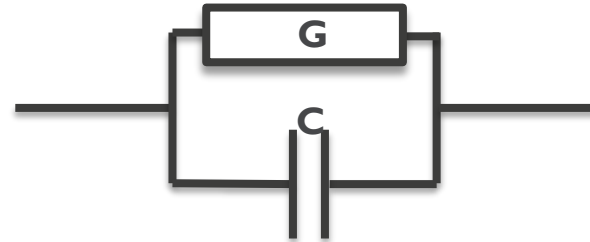
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Jozef Poortmans, and Bart Vermang*



PUBLIC

Admittance spectroscopy: Experimental setup

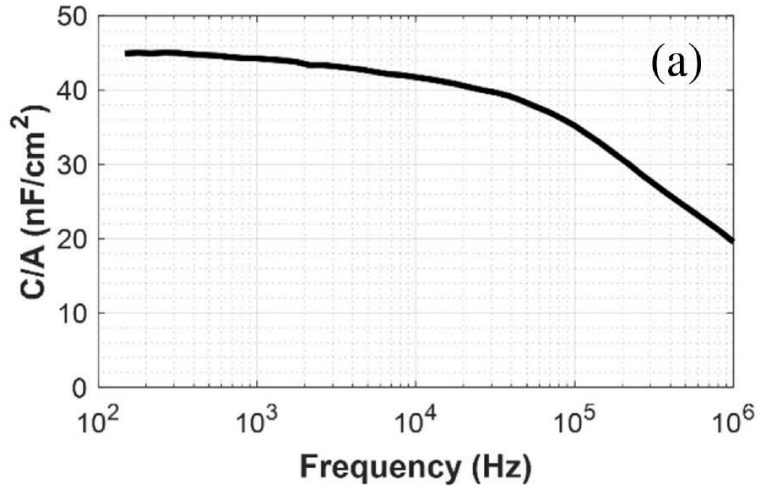
- CIGS solar cell sample (Mo/co-evap CIGS/CdS/i-ZnO/AZO)
- LCR-meter with DC-bias option (Agilent E4980A)
- Needle probes (4-point or 2-point)
- Measurement of the parallel capacitance and conductance at room temperature with:
 - 50 different frequencies varying logarithmically from 100 Hz to 1 MHz
 - 51 different bias voltages varying from -1.5 V to 1 V



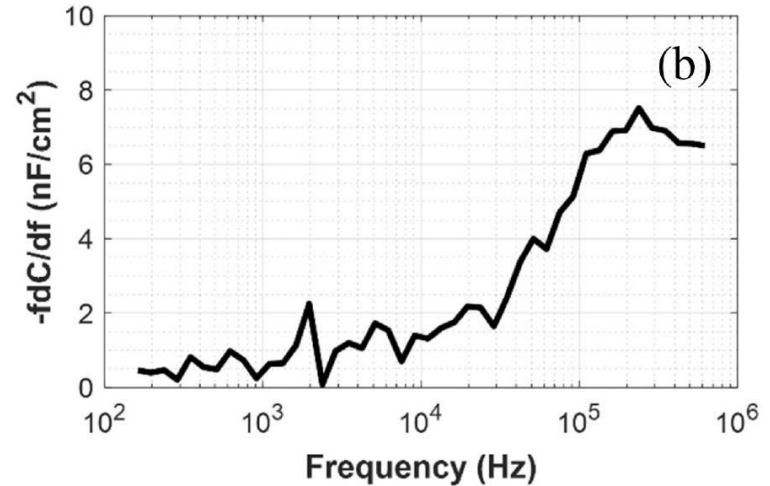
→ 50 x 51 (2550) measurement values for C and G

Measurement results

C versus f at 0V



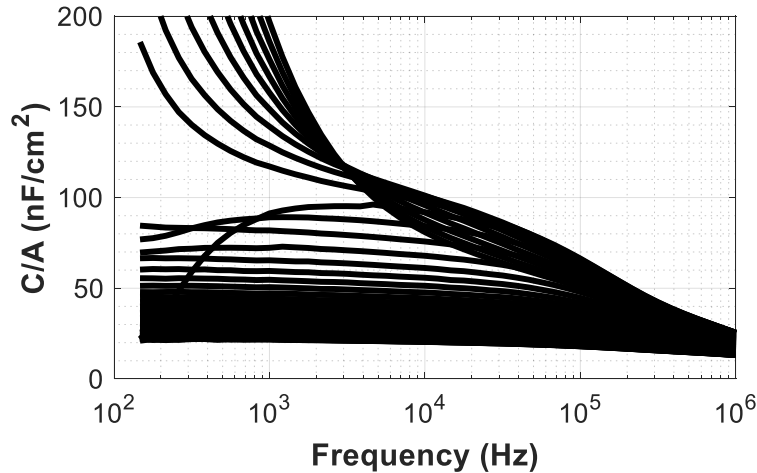
$-fdC/df$ versus f at 0V



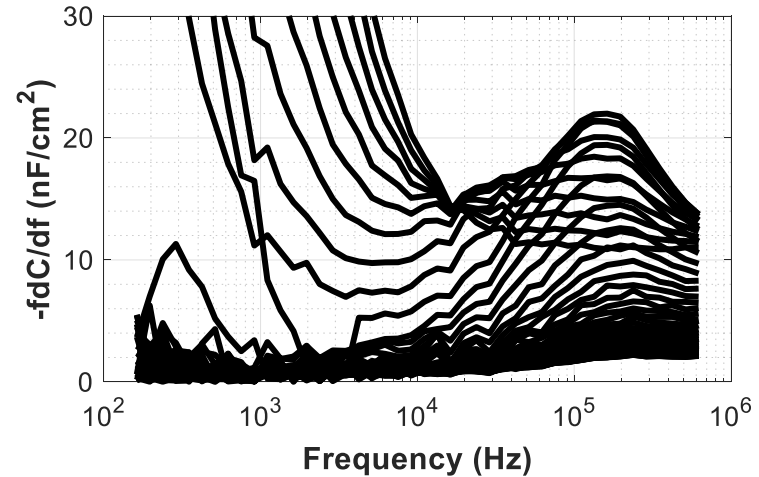
- Only room temperature data shown here.
- In general, measurements at different temperatures shown as well, in order to make an Arrhenius plot and to extract the activation energy \rightarrow not the focus here.
- We will investigate here what we can do with the data from the other 50 bias voltages.

Measurement results

C versus f for all voltages



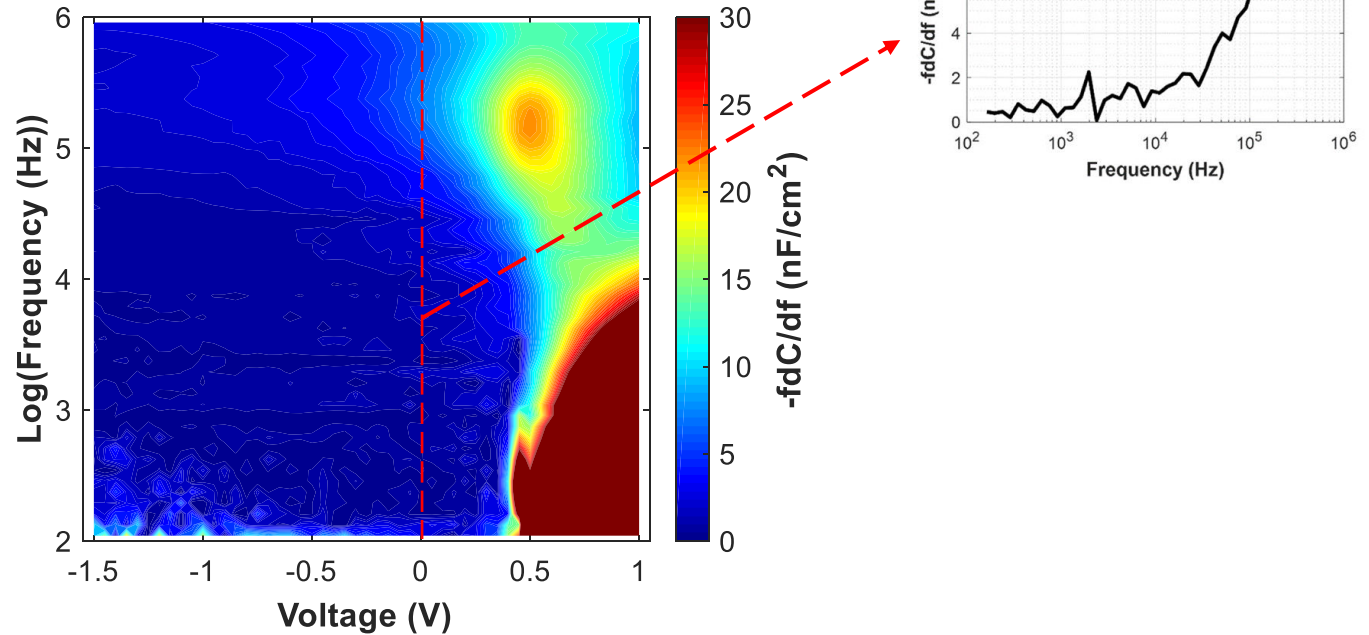
-fdC/df versus f for all voltages



- Only room temperature data shown here.
- Possible, but quite messy data, difficult to get valid information from this type of graph.

CVf - loss map¹

2 D map of $-fdC/df$ versus $\log(f)$ and voltage



- Better graphical representation of the data.
- Continuous response domains can be identified.
- Every response in this map corresponds to a charge loss event, basically a resistive response, therefore the name “CVf *loss map*”.

Loss map simulations: SCAPS!

SCAPS 3.3.0 Action Panel

Working point
 Temperature (K)
 Voltage (V)
 Frequency (Hz)
 Number of points

Series resistance yes no
 Shunt resistance yes no
 Rs: Ohm.cm² Rsh:
 S/cm² Gsh:

Action list **All SCAPS settings**

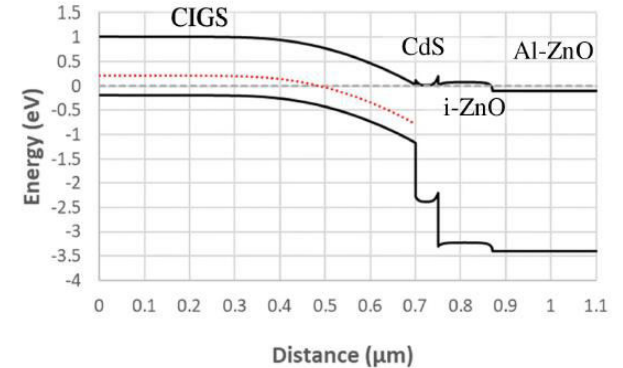
Illumination: Dark Light **Generation G(x):** From internal SCAPS calculation Read from file

Light source for internal G(x) calculation
 Spectrum file: Illuminated side: from right left
 Incident (or bias) light power (W/m²) sun or lamp:
 Spectrum cut off? yes no Short wavel. (nm) after cut-off:
 Long wavel. (nm) after ND:
 Neutral Density Transmission (%)

External file to read G(x) from
 Generation file:
 Ideal Light Current in file (mA/cm²)
 Transmission of attenuation filter (%)
 Ideal Light Current in cell (mA/cm²)

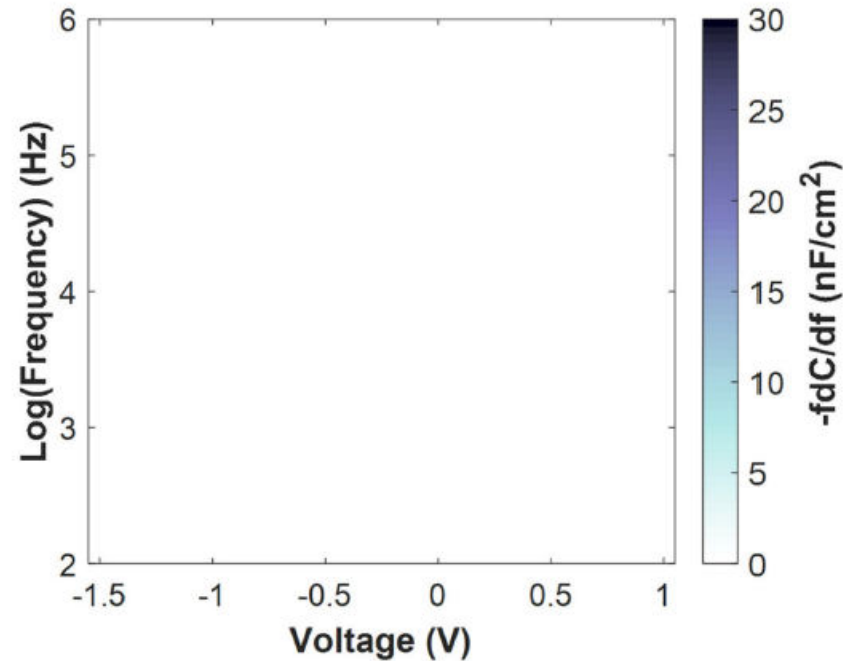
Action Pause at each step
 I-V V1 (V) V2 (V)
 C-V V1 (V) V2 (V)
 C-f f1 (Hz) f2 (Hz)
 QE (IPCE) WL1 (nm) WL2 (nm)
 number of points increment (V)

Set problem loaded definition file:



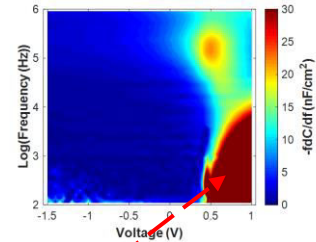
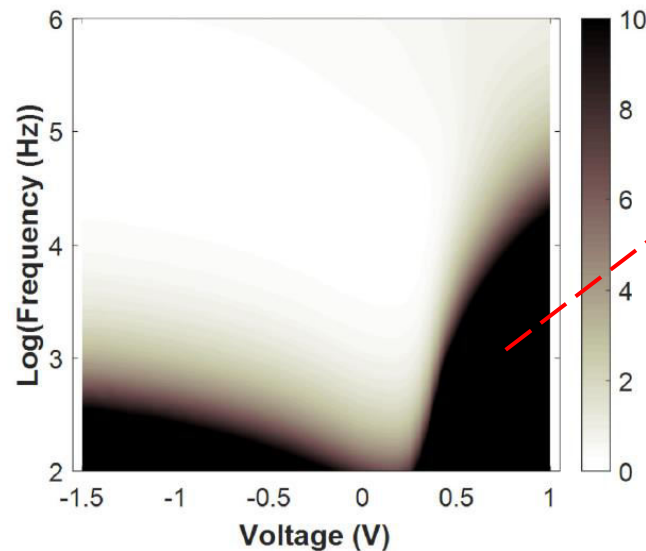
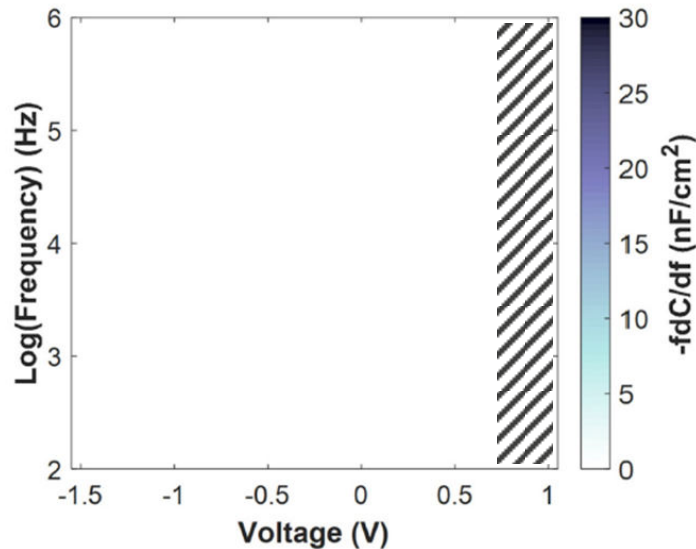
- Simulation of Capacitance of CIGS solar cell structure as a function of bias voltage and as a function of frequency.

Loss map simulations: No defects



- No defects in the solar cell structure lead to an empty loss map, as there are no losses involved.

Loss map simulations: shunt resistance

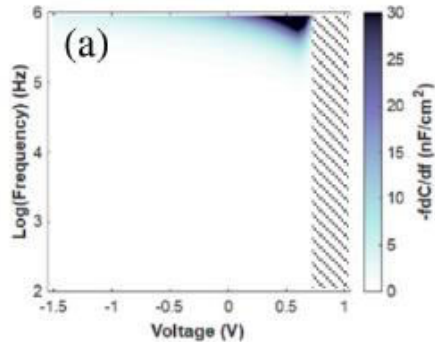


$$D = \frac{G_p}{2\pi f C_p}$$

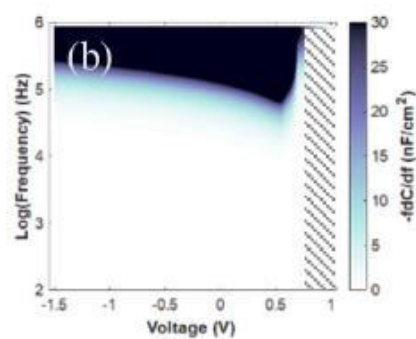
- The shunt resistance has no direct influence on the loss map.
- It does influence the dissipation factor though.
- If dissipation factor is too large, the tool cannot measure the capacitance accurately anymore.

Loss map simulations: series resistance

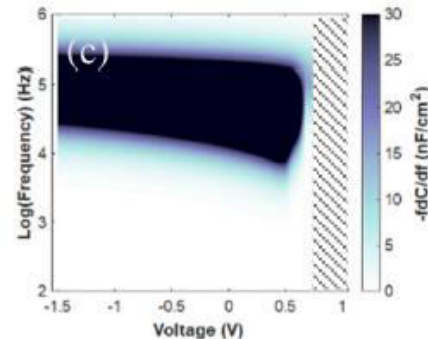
$R_s = 1 \Omega \text{ cm}^2$



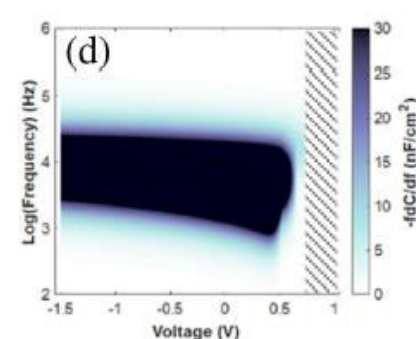
$R_s = 10 \Omega \text{ cm}^2$



$R_s = 100 \Omega \text{ cm}^2$



$R_s = 1000 \Omega \text{ cm}^2$

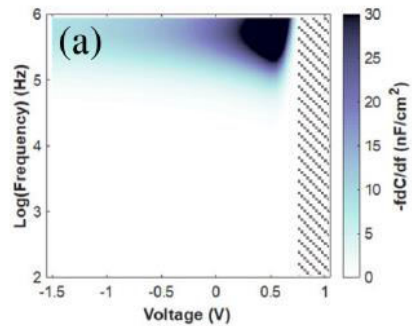


- Series resistance leads to an almost horizontal response in the loss map.
- Response frequency can be calculated with cut-off frequency of RC-circuit: $f_c^{-1} = 2\pi RC$.
- For typical series resistance values of solar cell devices only small response at frequencies around 1 MHz is visible.

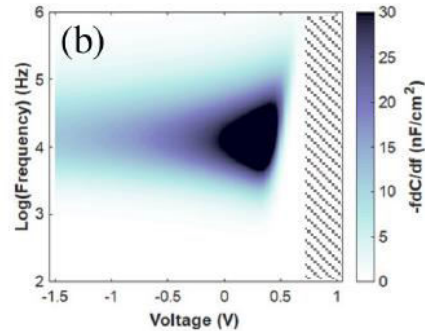
Loss map simulations: bulk defects in the CIGS

- 10^{16} cm^{-3} acceptor-like defects above the valence band edge energy of the CIGS.
- Capture cross-section of 10^{-15} cm^{-2} assumed.

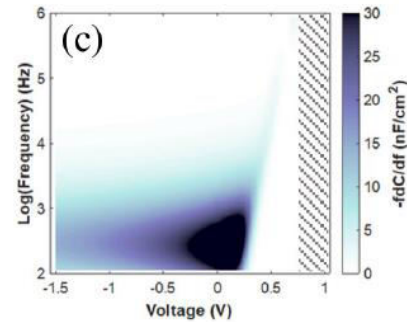
$E_a = 0.3 \text{ eV}$



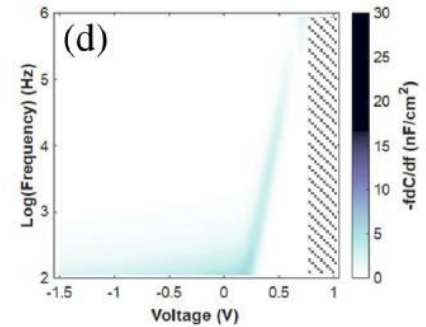
$E_a = 0.4 \text{ eV}$



$E_a = 0.5 \text{ eV}$



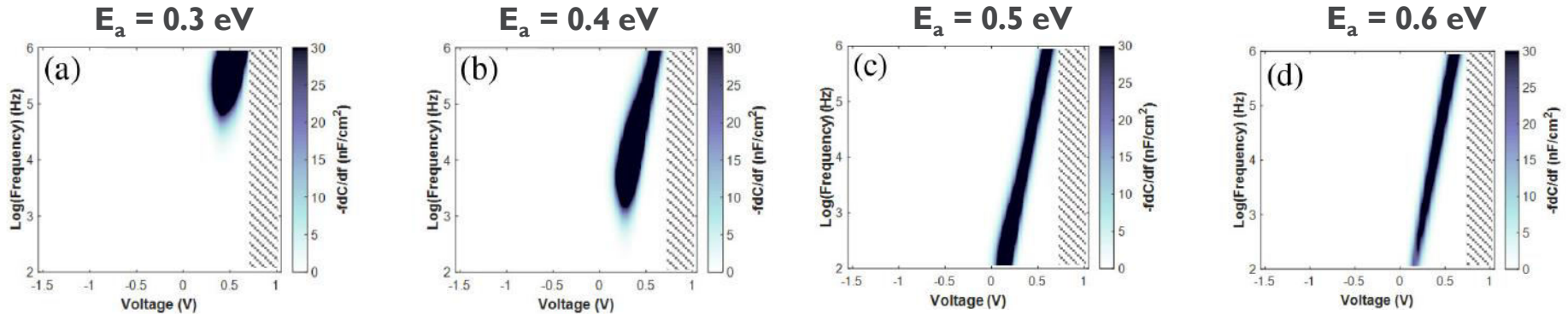
$E_a = 0.6 \text{ eV}$



- Broad response over the full bias range.
- The intensity of the response with respect to bias voltage follows the depletion layer capacitance.
- Exact determination of the activation energy needs temperature dependent-measurements.

Loss map simulations: defects at the CIGS/CdS interface

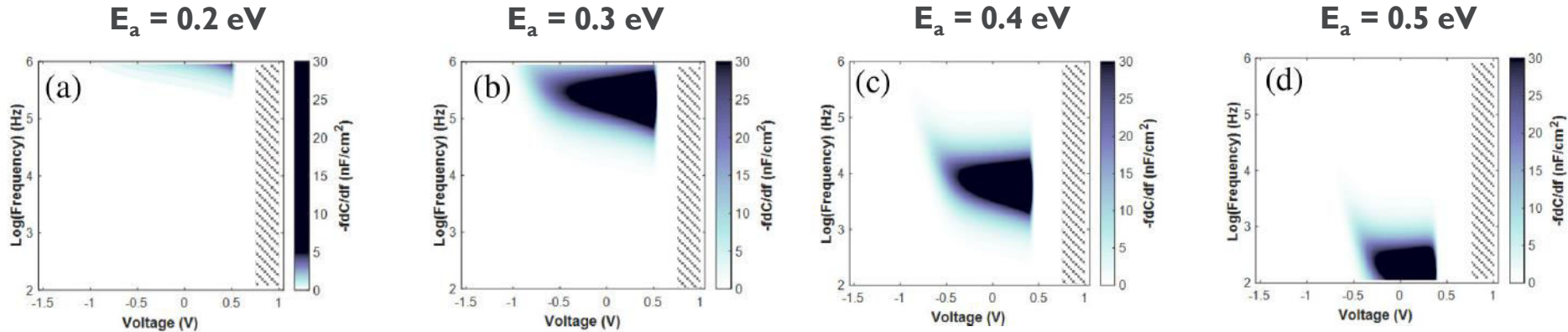
- $10^{12} \text{ cm}^{-2} \text{ eV}^{-1}$ acceptor-like defects above the valence band edge energy of the CIGS.
- Capture cross-section of 10^{-15} cm^{-2} assumed.



- Quite localized response over small bias range.
- Quite complex behavior:
 - If density too large \rightarrow Fermi level pinning (bias independent response)
 - Depends strongly on doping in CdS (can vary the Fermi level position at the interface)

Loss map simulations: barrier at the back contact

- Backside barrier with varying barrier height.

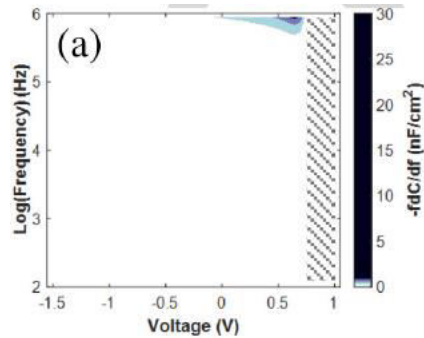


- Decrease in response frequency as barrier height increases.
- Slight upward tail.

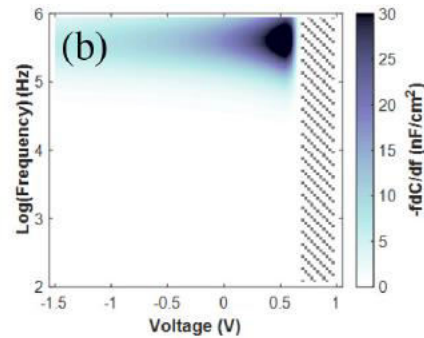
Loss map simulations: barrier at the CIGS/CdS interface

- Spike-like barrier at the CIGS-CdS interface with varying barrier height.

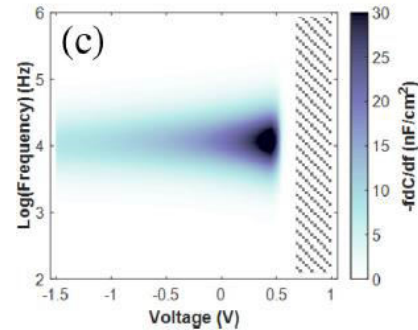
$E_a = 0.2 \text{ eV}$



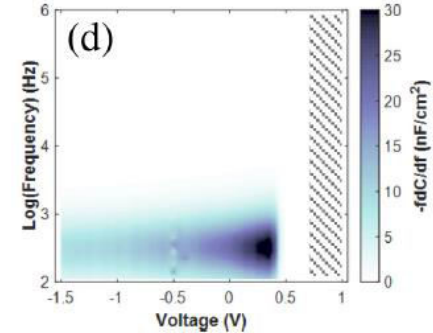
$E_a = 0.3 \text{ eV}$



$E_a = 0.4 \text{ eV}$



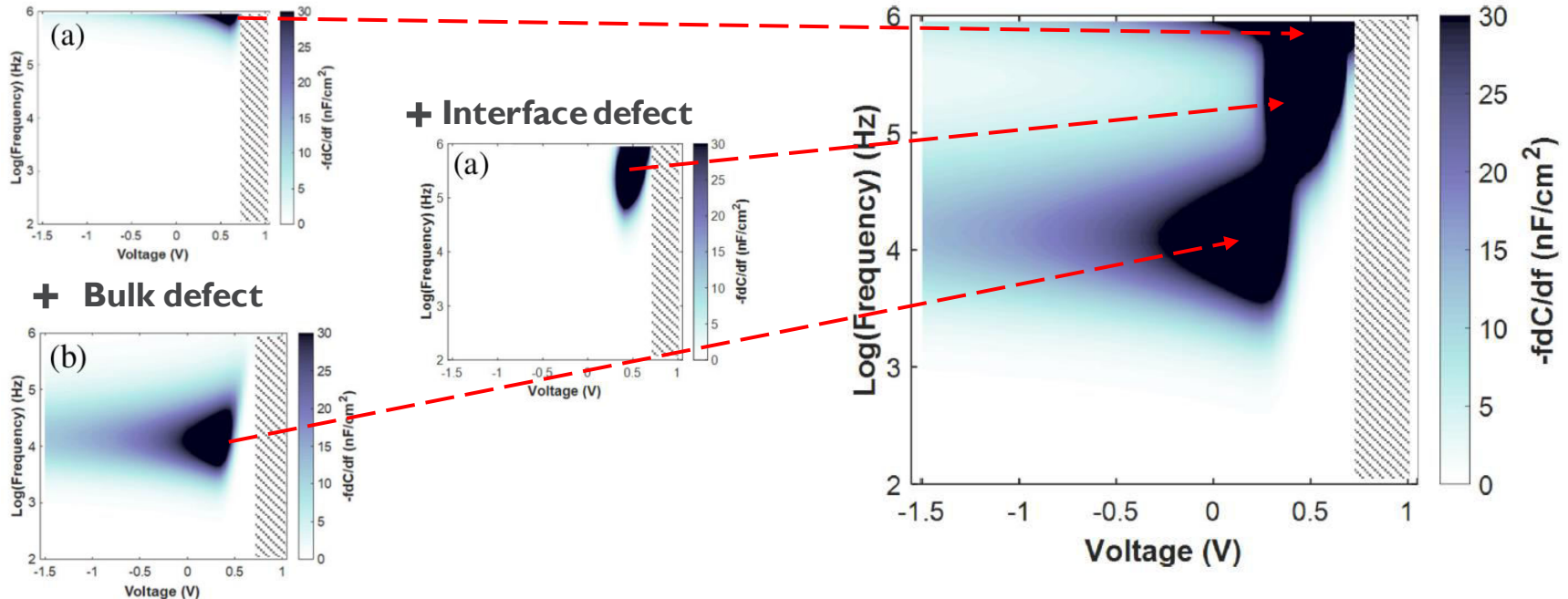
$E_a = 0.5 \text{ eV}$



- Decrease in response frequency as barrier height increases.
- Response frequency totally independent of bias voltage.

Loss map simulations: Different defects simultaneously

Series resistance



- Adding different defects in the solar cell structure at the same time, leads to a loss map where all the responses from the different defects add up.
- This is no longer true if one of the defects creates Fermi-level pinning, as that inhibits the movement of the Fermi level, possibly hiding some defect responses that otherwise would have been present.

Conclusions

- We have introduced a “CVf loss map”, which plots $-fdC/df$ as a function of bias voltage and frequency.
- We have then made SCAPS simulations in order to simulate the loss map for different typical defects that can be present in a solar cell structure.
- Even though quite complex, these loss maps might be helpful for finding possible root causes for defect responses in solar cells.

Acknowledgements

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